



GE Canada

Electronic Products Repair

Test Instructions for

4006L6501 G001

Device Number

Drive Interface Card

Description of Device

Originated By: Rogério Cordeiro
Typed Name

Date: May 6, 2005
mm/dd/yy

Approved By: 
Signature

Approval Date: May 6, 2005
mm/dd/yy

TEST INSTRUCTIONS
PREVIOUS REVISION SHEET

4006L6501 G001

Device Number

Drive Interface Card

Description of Device

[illegible]

TEST INSTRUCTIONS



Drive Interface Card
4006L6501 G001
Date: May 6, 2005

Location: Book or file File

Pg.: 3/4

1. PURPOSE:

- a. Static and dynamic test procedures for Drive Interface Card 4006L6501 G001

2. ELEMENTARY:

3. EQUIPMENT:

- a. Fluke 9010A Programmer
- b. Fluke 80188 Pod
- c. Oscilloscope
- d. DVM (Volt Meter)
- e. SP3200 Test Panel
- f. 2 - 50 ribbon cables
- g. Lambda Power Supply
- h. 6501 P.S. Box *part # 00974*
- i. JD Connector

4. SET UP:

- a. Connect cables to SP3200 Jig and UUT.
- b. Connect power cables and required tools

5. PROCEDURE:

- a. Setup Fluke Trouble shooter and pod. Load program tape 4006L6501 dated Jan. 25, 1995.
- b. Connect the 50 pin ribbon cables from JR and JS on the SP3200 Test Panel to the JR and JS respectively on the card under test.
- c. Pull switch (+15V) on the Test Panel towards 32pin connector.
- d. Connect the Lambda power supply to 120 VAC.
- e. Connect the Lambda Power Supply to the 6501 P.S. Box and connect the box to the card under test. Connect the +5V and Com to the Test Panel.
- f. Remove CPU (U1) and connect the pod to the U1 CPU Socket. If the socket is the old style, it may need to be shave down in order for the pod to be connected. If it is the CMOS style, and CPU adapter is required.
- g. Once all connections are made, power up the Variac and run Program 10. If an active interrupt @F00064 - Loop? occurs, just press the CONT. key and continue with the program on the tape.
- h. Once all tests are complete. Remove all cable and re-install CPU.
- i. Install card into SP3200 Drive and follow SP3200 Test Instruction in order to setup and run the drive.
- j. If at any time you wish to skip through parts of the program without starting from the beginning, do the following:
 - i. Hit Program 10 (to open the program)
 - ii. Keep hitting "More", until you come to "Bus Test Complete"
 - iii. Hit "Goto" button and enter the letter "E"
 - iv. Hit "Program" button (to close the program)
 - v. Hit "Execute Program" button and 10 and then enter.

TEST INSTRUCTIONS



Drive Interface Card
4006L6501 G001
Date: May 6, 2005

Location: Book or file File

Pg.: 4/4

6. UPGRADES: *For G001 ONLY*

- a. Rev0 to Rev1
 - i. Remove U19=0177A1644 P373=SN74LS373 change quantity of part list to 1.
 - ii. Change R45=0177A1460 P029=100Ω ¼W 1% to 0177A1460 P223=10kΩ ¼W 1%.
 - iii. Move + marking for C12 to opposite side close to C17.
- b. Rev1 to Rev2
 - i. Remove U22.
 - ii. Add socket for U22 0177A1517 P002.
 - iii. Add U22=0239A2506 P001=DS1225AB.
 - iv. Move + marking for C12 to Lead hole above J1 (already done in previous revision).
 - v. Enlarge mounting holes to 0.25"
 - vi. Add Tie rap to hold U22
- c. All NEC counters to be replaced with Intel counters.
- d. 4006L6501AAG001 Refers to the baseboard, the hardware level.
 - i. Rev0 to Rev1 corrects mistake in masking of card.
 - ii. Rev1 to Rev2 corrects BRAM problems.
 - iii. 4006L6501ABG001 Silpac 3200 drive and high performance drive.
 - iv. 4006L6501ADG001 Silpac 3200 12 pulse drive.
 - v. 4006L6501AEG001 Silpac 3200 plus drive.

7. END:

NOTE: - LASTEST IS A 4006L6501AAG002 REV1
-- NO UPDATES REQUIRED

ISS*

Data Map

IO - 230
IO - 212
215
231
211
214
232

RUN_PB
16K_PB
12K_PB
5K_PB
JUGR_PB
JUGR_PB
STOP_PB

649	INSTOL	19+
50	CLIF	19+
51		19+16
52	POST	189
53	TOL	19+16
54	STOP	19+
55	LOCAL	19+16
56		19+16
57		19+16
58		19+17
59		19+17
60	- 3540	19+17
61		19+17
62		19+17
63	- M1	19+17
64		19+17

2. TROUBLESHOOTING (continued)

2.2 INTERPRETING CARD-MOUNTED LEDs (continued)

LED	DESCRIPTION	RECOMMENDED ACTION
1	80188 MICROPROCESSOR TEST FAILED	REPLACE DCC
2	STATIC RAM TEST FAILED	" "
3	EPROM CHECKSUM TEST FAILED	REPLACE EPROMS or DCC
4	NON-VOLATILE RAM TEST FAILED	REPLACE DCC
5	80188 TIMER TEST FAILED	" "
6	8254 TIMER TEST FAILED	" "
7	INTERRUPT CONTROLLER TEST FAILED	" "
8	DUAL PORT RAM TEST FAILED	SEE TABLE 1.4: "DUAL PORT COMM. BAD"

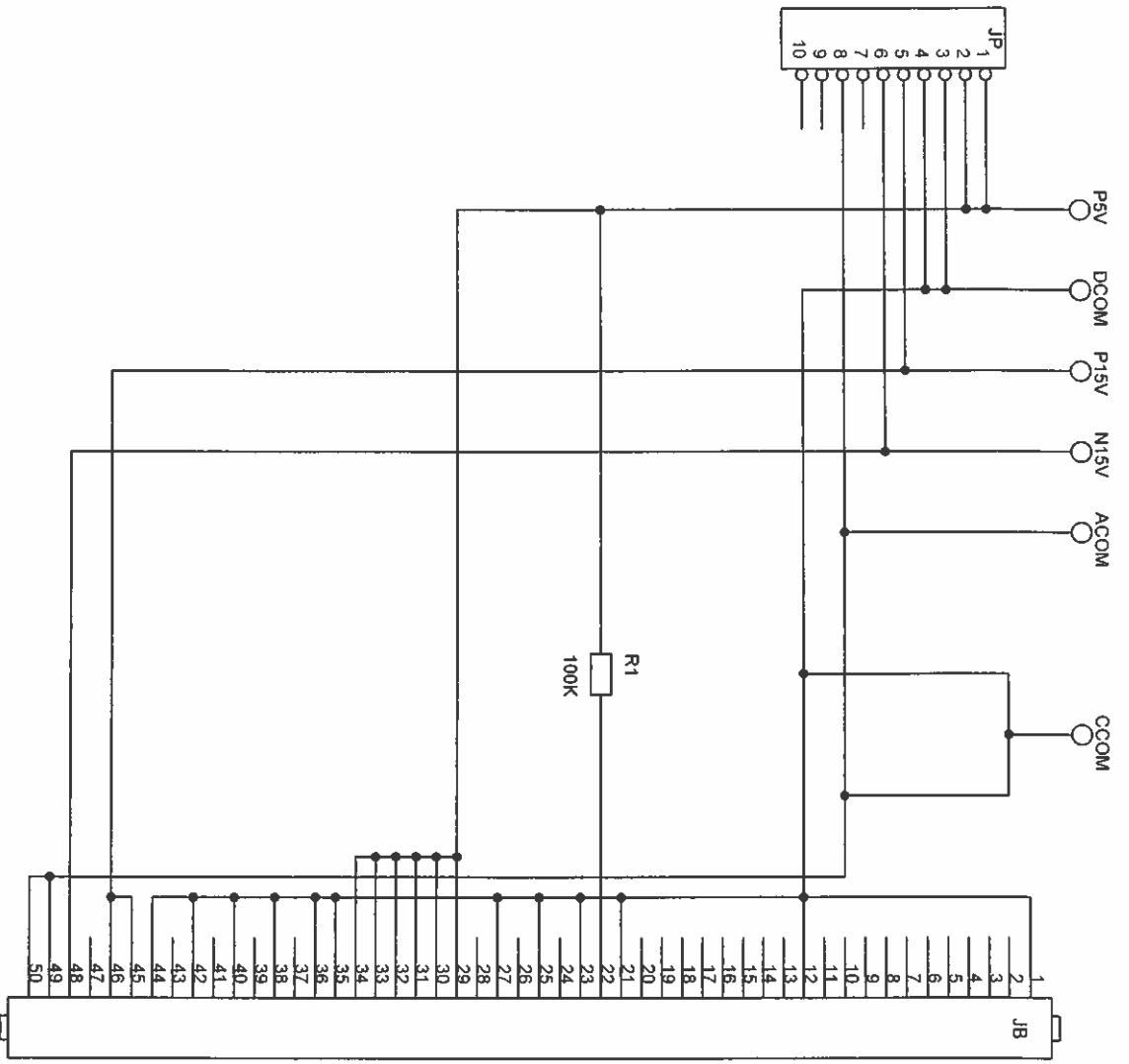
TABLE 2.1 - DRIVE CONTROL CARD LED DIAGNOSTIC REPORTING

LED	DESCRIPTION	RECOMMENDED ACTION
1	80188 MICROPROCESSOR TEST FAILED	REPLACE DIC
2	STATIC RAM TEST FAILED	" "
3	EPROM CHECKSUM TEST FAILED	REPLACE EPROMS or DIC
4	LCD DISPLAY TEST FAILED (Note: LED on steady, not flashing for LCD test only)	REPLACE RIBBON CABLE, LCD DISPLAY MODULE, or DIC

TABLE 2.2 - DRIVE INTERFACE CARD LED DIAGNOSTIC REPORTING

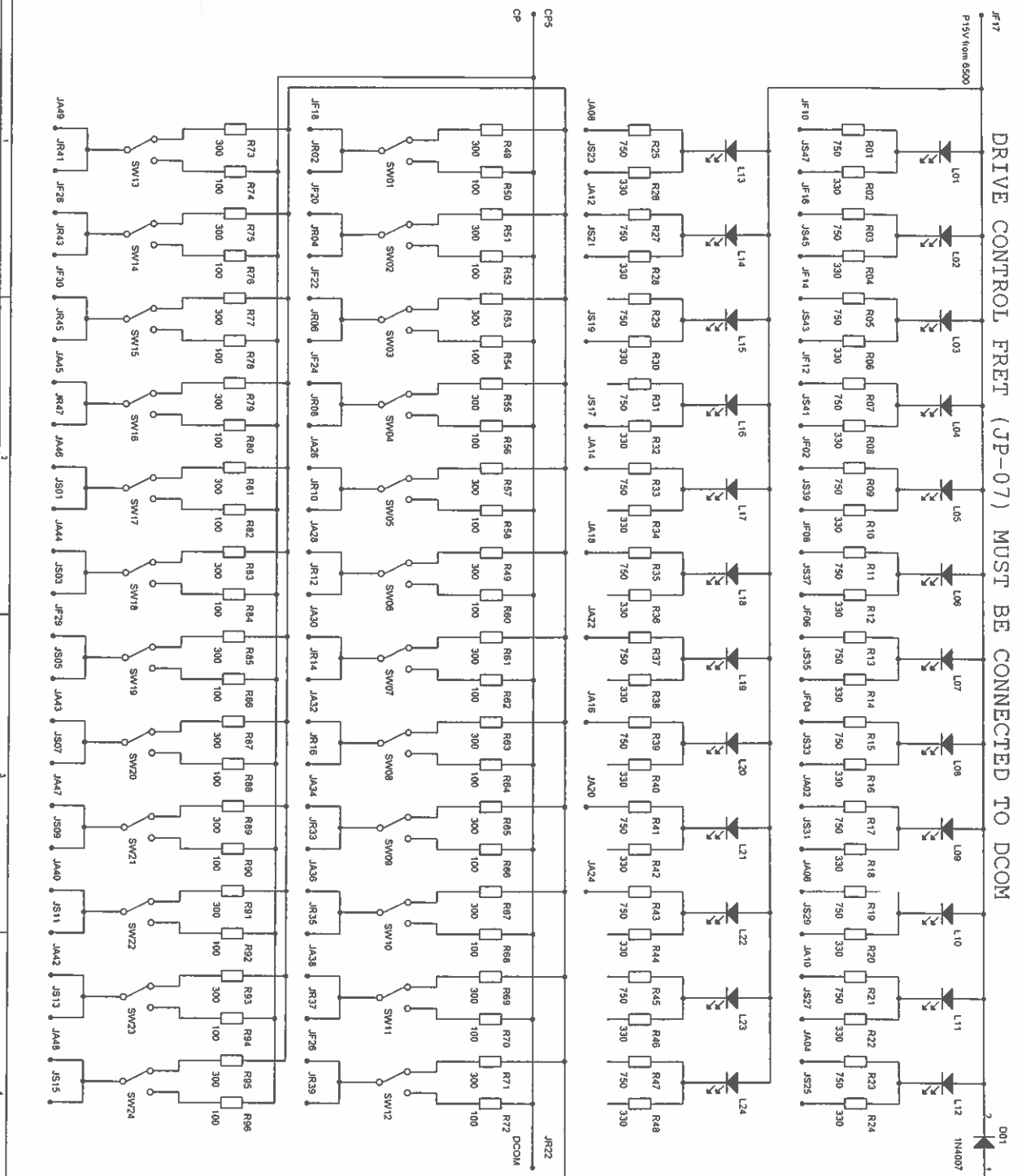
LED	DESCRIPTION	RECOMMENDED ACTION
1	80188 MICROPROCESSOR TEST FAILED	REPLACE HCC
2	STATIC RAM TEST FAILED	" "
3	EPROM CHECKSUM TEST FAILED	REPLACE EPROMS or HCC
4	LCD DISPLAY TEST FAILED (Note: LED on steady, not flashing for LCD test only)	REPLACE RIBBON CABLE, LCD DISPLAY MODULE, or HCC
5	BATTERY-BACKED RAM TEST FAILED	REPLACE HCC
6	80188 TIMER TEST FAILED	" "
7	8254 TIMER TEST FAILED	" "
8	INTERRUPT CONTROLLER TEST FAILED	" "

TABLE 2.3 - HELPER CONTROL CARD LED DIAGNOSTIC REPORTING



GE Canada		
Title	TL#00819 & TL#00974 4006L6501	
Size	Document Number	Rev
A	TL#00819 & TL#00974 4006L6501	
Date:	Friday, January 06, 2006	Sheet 1 of 1

DRIVE CONTROL FRET (JP-07) MUST BE CONNECTED TO DCOM



F1		P5V	
JA02 - R17	JA26 - SW05		
JA04 - R23	JA28 - SW06		
JA06 - R19	JA30 - SW07		
JA08 - R25	JA32 - SW08		
JA10 - R21	JA34 - SW09		
JA12 - R27	JA36 - SW10		
JA14 - R33	JA38 - SW11		
JA16 - R39	JA44 - SW18		
JA18 - R35	JA45 - SW16		
JA20 - R41	JA46 - SW17		
JA22 - R37	JA49 - SW13		
JA24 - R43	JA48 - SW24		
	JA42 - SW23		
	JA43 - SW20		
	JA47 - SW21		